Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/706,642	TANAKA, KAZUE
Examiner	Art Unit

Jaworski Francis J.

3768

SEARCHED					
Class	Subclass	Date	Examiner		
601	2-4	12/3/2007	FJJ		
606	167-171				
604	22				
702	65-66				
	75-77				
	•				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
606	169	12/3/2007	FJJ		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
PLL or (phase\$1lock\$3) or sweep or swept and (vibrat\$5 or ultraso\$9), tool or instrument or probe	12/3/2007	FJJ		